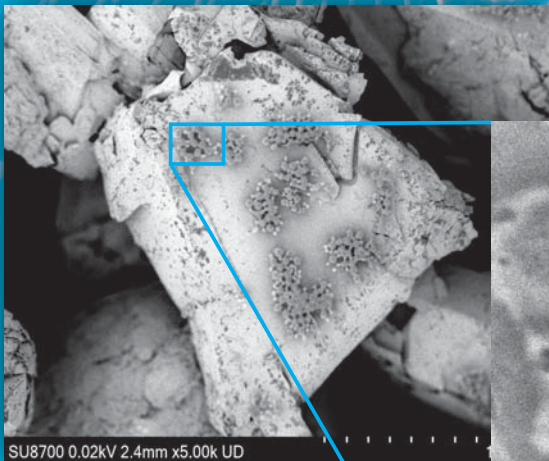
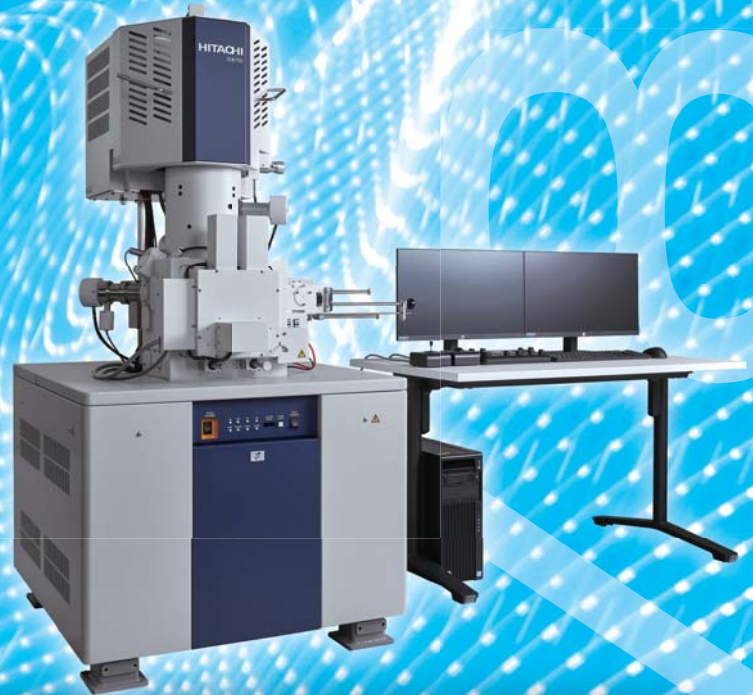


SCANNING ELECTRON MICROSCOPE

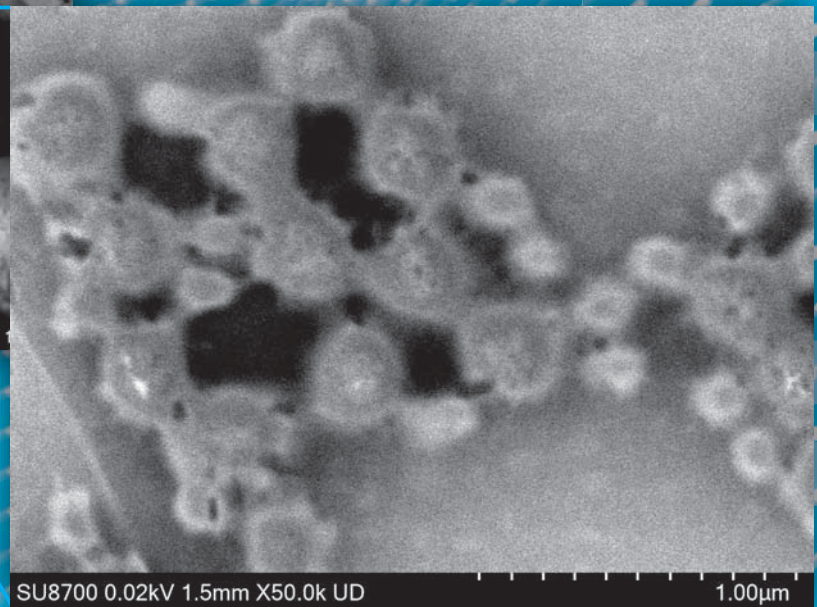
# SU8700

## A New World Revealed by Ultra-Low Voltage Imaging

An example of LIB material image, the shape of the binder is clearly visible with damage suppressed by ultra-low voltage. (No stage bias applied)



Specimen: Lithium-ion battery  
anode material  
Accelerating voltage: 20 V  
Specimen courtesy of  
Mr. Hajime Okui, DAINEN MATERIAL Co., Ltd.



### Versatile information acquisition capability and low accelerating voltage imaging performance

- ◆ Equipped with Schottky emitter for ultra-low voltage imaging and fast analysis
- ◆ Superb electron optics and detection system for expanding imaging technique and specimen
- ◆ Acceleration voltage can go down to 10 V without stage bias voltage

### Supports automatic image acquisition

- ◆ Equipped with an automatic optical alignment feature
- ◆ Automatic data acquisition recipes can be created according to user workflow

### Supports for large-volume data acquisition

- ◆ Acquire high-resolution data up to 40,960 x 30,720 pixels
- ◆ Simultaneous acquisition of signals up to 6 channels

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